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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

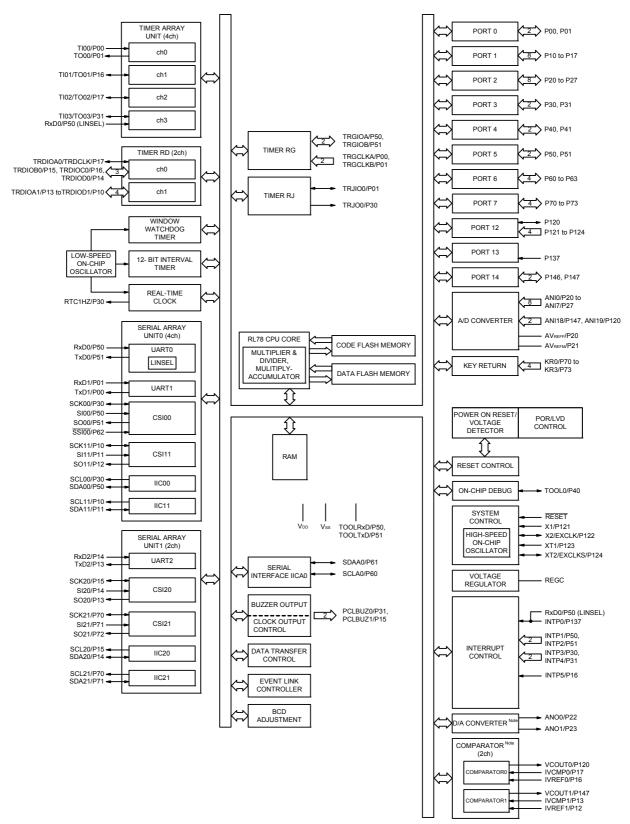
Details

Product Status	Obsolete
Core Processor	RL78
Core Size	16-Bit
Speed	32MHz
Connectivity	CSI, I ² C, LINbus, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	38
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	4K x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 5.5V
Data Converters	A/D 12x8/10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	52-LQFP
Supplier Device Package	52-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f104jcafa-v0

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

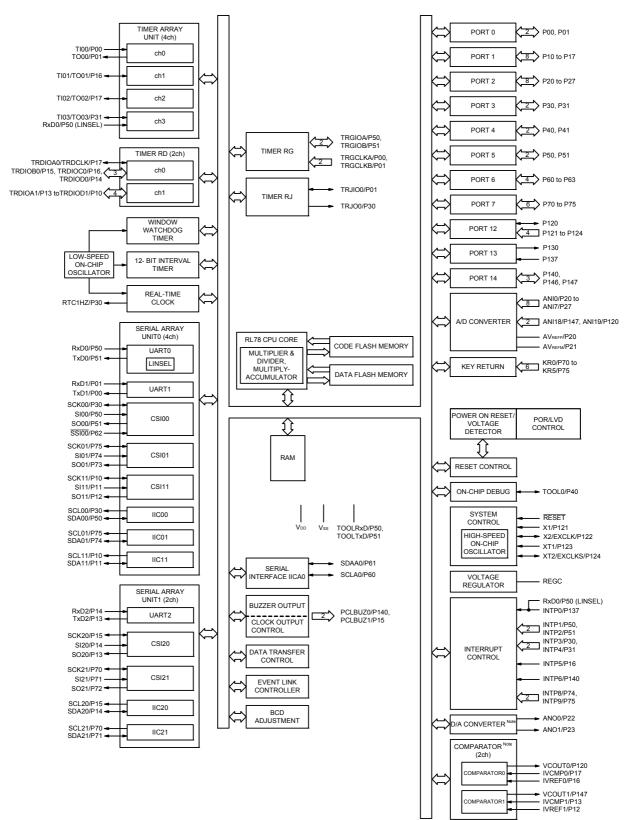
1.5.5 44-pin products



Note Mounted on the 96 KB or more code flash memory products.



1.5.6 48-pin products



Note Mounted on the 96 KB or more code flash memory products.



Note	The flash library uses RAM in self-programming and rewriting of the data flash memory.
	The target products and start address of the RAM areas used by the flash library are shown below.
	R5F104xJ (x = F, G, J, L, M, P): Start address F9F00H
	For the RAM areas used by the flash library, see Self RAM list of Flash Self-Programming Library for RL78 Family
	(R20UT2944).



(R20UT2944).

 Note
 The flash library uses RAM in self-programming and rewriting of the data flash memory.

 The target products and start address of the RAM areas used by the flash library are shown below.

 R5F104xL (x = G, L, M, P): Start address F3F00H

 For the RAM areas used by the flash library, see Self RAM list of Flash Self-Programming Library for RL78 Family

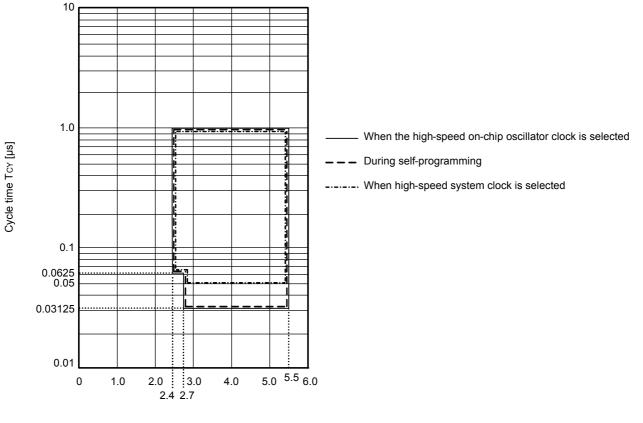


- Note 1. Total current flowing into VDD, EVDD0, and EVDD1, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD0, and EVDD1, or Vss, EVss0, and EVss1. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, D/A converter, comparator, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
 Note 2. During HALT instruction execution by flash memory.
- Note 3. When high-speed on-chip oscillator and subsystem clock are stopped.
- **Note 4.** When high-speed system clock and subsystem clock are stopped.
- **Note 5.** When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1). The current flowing into the RTC is included. However, not including the current flowing into the 12-bit interval timer and watchdog timer.
- Note 6. Not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer.
- Note 7. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.
 - HS (high-speed main) mode: $2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}_{@}1 \text{ MHz}$ to 32 MHz
 - 2.4 V \leq VDD \leq 5.5 V@1 MHz to 16 MHz
 - LS (low-speed main) mode: $1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}$ @1 MHz to 8 MHz
 - LV (low-voltage main) mode: $1.6 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}$ @1 MHz to 4 MHz
- Note 8. Regarding the value for current to operate the subsystem clock in STOP mode, refer to that in HALT mode.
- Remark 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
- Remark 2. fHOCO: High-speed on-chip oscillator clock frequency (64 MHz max.)
- **Remark 3.** file: High-speed on-chip oscillator clock frequency (32 MHz max.)
- **Remark 4.** fsuB: Subsystem clock frequency (XT1 clock oscillation frequency)
- Remark 5. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is TA = 25°C



Minimum Instruction Execution Time during Main System Clock Operation

TCY vs VDD (HS (high-speed main) mode)



Supply voltage VDD [V]



(6) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode)

(TA = -40 to +85°C, 1.6 V \leq EVDD0 = EVDD1 \leq VDD \leq 5.5 V, Vss = EVss0 = EVss1 = 0 V)

(2/2)

Parameter	Symbol		Conditions		-speed main) node	•	-speed main) mode	•	oltage main) node	Unit																	
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.																		
Transfer rate	transmission $\begin{array}{l} 4.0 \ V \leq EV_{DD0} \leq 5.5 \ V, \\ 2.7 \ V \leq V_b \leq 4.0 \ V \end{array}$		· · · · ·		Note 1		Note 1		Note 1	bps																	
			Theoretical value of the maximum transfer rate C_b = 50 pF, R_b = 1.4 kΩ, V_b = 2.7 V		2.8 Note 2		2.8 Note 2		2.8 Note 2	Mbps																	
		$2.7 \text{ V} \leq \text{EV}_{\text{DD0}} < 4.0 \text{ V},$ $2.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}$		Note 3		Note 3		Note 3	bps																		
			Theoretical value of the maximum transfer rate C_b = 50 pF, R_b = 2.7 kΩ, V_b = 2.3 V		1.2 Note 4		1.2 Note 4		1.2 Note 4 Mb	Mbps																	
															l				-	$\begin{array}{l} 1.8 \ V \leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V \end{array}$		Notes 5, 6		Notes 5, 6		Notes 5, 6	bps
			Theoretical value of the maximum transfer rate C_b = 50 pF, R_b = 5.5 kΩ, V_b = 1.6 V		0.43 Note 7		0.43 Note 7		0.43 Note 7	Mbps																	

Note 1. The smaller maximum transfer rate derived by using fMCK/6 or the following expression is the valid maximum transfer rate. Expression for calculating the transfer rate when $4.0 \text{ V} \le \text{EV}\text{DD0} \le 5.5 \text{ V}$ and $2.7 \text{ V} \le \text{Vb} \le 4.0 \text{ V}$

1

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) =
$$\frac{\frac{1}{|\text{Transfer rate} \times 2|} - \{-C_b \times R_b \times \ln(1 - \frac{2.2}{|V_b|})\}}{(\frac{1}{|\text{Transfer rate}|}) \times \text{Number of transferred bits}}$$

* This value is the theoretical value of the relative difference between the transmission and reception sides

Note 2.This value as an example is calculated when the conditions described in the "Conditions" column are met.Refer to Note 1 above to calculate the maximum transfer rate under conditions of the customer.

Note 3. The smaller maximum transfer rate derived by using fMCK/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V \leq EVDD0 < 4.0 V and 2.3 V \leq Vb \leq 2.7 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\} \times 3}$$
Baud rate error (theoretical value) =
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}}$$

* This value is the theoretical value of the relative difference between the transmission and reception sides



(3/3)

(8) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output)

Parameter	Symbol	Conditions		peed main) ode	· · ·	peed main) ode		ltage main) ode	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SIp setup time (to SCKp↓) ^{Note 1}	tsıĸı		44		110		110		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD0} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	44		110		110		ns
		$ \begin{split} & 1.8 \ \text{V} \leq \text{EV}_{\text{DD0}} < 3.3 \ \text{V}, \\ & 1.6 \ \text{V} \leq \text{V}_{\text{b}} \leq 2.0 \ \text{V} \ \text{Note} \ ^2, \\ & \text{C}_{\text{b}} = 30 \ \text{pF}, \ \text{R}_{\text{b}} = 5.5 \ \text{k}\Omega \end{split} $	110		110		110		ns
SIp hold time (from SCKp↓) ^{Note 1}	tksi1		19		19		19		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD0} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	19		19		19		ns
		$\label{eq:linear} \begin{array}{l} 1.8 \ V \leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V \ ^{Note \ 2}, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	19		19		19		ns
Delay time from SCKp↑ to SOp output ^{Note 1}	tkso1			25		25		25	ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD0} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$		25		25		25	ns
		$ \begin{split} & 1.8 \ \text{V} \leq \text{EV}_{\text{DD0}} < 3.3 \ \text{V}, \\ & 1.6 \ \text{V} \leq \text{V}_{b} \leq 2.0 \ \text{V} \ ^{\text{Note 2}}, \\ & \text{C}_{b} = 30 \ \text{pF}, \ \text{R}_{b} = 5.5 \ \text{k}\Omega \end{split} $		25		25		25	ns

$(TA = -40 \text{ to } +85^{\circ}C, 1.8 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD} \le 5.5 \text{ V}, \text{ Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Note 1. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Note 2. Use it with $EV_{DD0} \ge V_b$.

(**Remarks** are listed on the next page.)



Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (for the 30- to 52-pin products)/EVDD tolerance (for the 64- to 100-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

Parameter	Symbol	Conditions	HS (high-speed r mode	nain)	LS (low-speed m mode	nain)	LV (low-voltage r mode	main)	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Data setup time (reception)	tsu:dat	$\begin{array}{l} 4.0 \; V \leq EV_{DD0} \leq 5.5 \; V, \\ 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 50 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	1/fмск + 135 Note 3		1/fmck + 190 Note 3		1/fмск + 190 Note 3		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD0} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	1/fмск + 135 Note 3		1/fmck + 190 Note 3		1/fmck + 190 Note 3		ns
		$\begin{array}{l} 4.0 \; V \leq EV_{DD0} \leq 5.5 \; V, \\ 2.7 \; V \leq V_{b} \leq 4.0 \; V, \\ C_{b} = 100 \; pF, \; R_{b} = 2.8 \; k\Omega \end{array}$	1/fмск + 190 Note 3		1/fmck + 190 Note 3		1/fмск + 190 Note 3		ns
		$\begin{array}{l} 2.7 \; V \leq EV_{DD0} < 4.0 \; V, \\ 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 100 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	1/fмск + 190 Note 3		1/fmck + 190 Note 3		1/f _{MCK} + 190 Note 3		ns
		$\begin{array}{l} 1.8 \; V \leq EV_{DD0} < 3.3 \; V, \\ 1.6 \; V \leq V_{b} \leq 2.0 \; V \; ^{Note 2}, \\ C_{b} = 100 \; pF, \; R_{b} = 5.5 \; k\Omega \end{array}$	1/fмск + 190 Note 3		1/fmck + 190 Note 3		1/fмск + 190 Note 3		ns
Data hold time (transmission)	thd:dat	$\begin{array}{l} 4.0 \; V \leq EV_{DD0} \leq 5.5 \; V, \\ 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 50 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	0	305	0	305	0	305	ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD0} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	0	305	0	305	0	305	ns
			0	355	0	355	0	355	ns
		$\label{eq:2.7} \begin{array}{l} 2.7 \; V \leq EV_{DD0} < 4.0 \; V, \\ 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 100 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	0	355	0	355	0	355	ns
		$ \begin{split} & 1.8 \; \text{V} \leq \text{EV}_{\text{DD0}} < 3.3 \; \text{V}, \\ & 1.6 \; \text{V} \leq \text{V}_{b} \leq 2.0 \; \text{V} \; ^{\text{Note 2}}, \\ & \text{C}_{b} = 100 \; \text{pF}, \; \text{R}_{b} = 5.5 \; \text{k}\Omega \end{split} $	0	405	0	405	0	405	ns

(10) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified I²C mode)

(TA = -40 to +85°C, 1.8 V \leq EVDD0 = EVDD1 \leq VDD \leq 5.5 V, Vss = EVss0 = EVss1 = 0 V)

(2/2)

Note 1. The value must also be equal to or less than fmck/4.

Note 2. Use it with $EV_{DD0} \ge V_b$.

Note 3. Set the fmck value to keep the hold time of SCLr = "L" and SCLr = "H".

Caution Select the TTL input buffer and the N-ch open drain output (VDD tolerance (for the 30- to 52-pin products)/EVDD tolerance (for the 64- to 100-pin products)) mode for the SDAr pin and the N-ch open drain output (VDD tolerance (for the 30- to 52-pin products)/EVDD tolerance (for the 64- to 100-pin products)) mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

(**Remarks** are listed on the next page.)



(3) When reference voltage (+) = VDD (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = Vss (ADREFM = 0), target pin: ANI0 to ANI14, ANI16 to ANI20, internal reference voltage, and temperature sensor output voltage

(TA = -40 to +85°C, 1.6 V \leq EVDD0 = EVDD1 \leq VDD \leq 5.5 V, Vss = EVss0 = EVss1 = 0 V, Reference voltage (+) = VDD, Reference voltage (-) = Vss)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error Note 1	AINL	10-bit resolution	$1.8~\text{V} \leq \text{V}_{\text{DD}} \leq 5.5~\text{V}$		1.2	±7.0	LSB
			1.6 V \leq VDD \leq 5.5 V Note 3		1.2	±10.5	LSB
Conversion time	tconv	10-bit resolution	$3.6 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	2.125		39	μs
		Target pin: ANI0 to ANI14, ANI16 to ANI20	$2.7 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	3.1875		39	μs
			$1.8 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	17		39	μs
			$1.6 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	57		95	μs
		10-bit resolution	$3.6 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	2.375		39	μs
		Target pin: internal reference voltage, and temperature sensor output voltage	$2.7 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	3.5625		39	μs
		(HS (high-speed main) mode)	$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μs
Zero-scale error Notes 1, 2	Ezs	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$			±0.60	%FSR
			$1.6~V \leq V_{DD} \leq 5.5~V~\text{Note}~3$			±0.85	%FSR
Full-scale error Notes 1, 2	Efs	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$			±0.60	%FSR
			1.6 V \leq VDD \leq 5.5 V Note 3			±0.85	%FSR
Integral linearity error Note 1	ILE	10-bit resolution	$1.8 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$			±4.0	LSB
			$1.6 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}$ Note 3			±6.5	LSB
Differential linearity error	DLE	10-bit resolution	$1.8~\text{V} \leq \text{V}_\text{DD} \leq 5.5~\text{V}$			±2.0	LSB
Note 1			$1.6 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}$ Note 3			±2.5	LSB
Analog input voltage	VAIN	ANI0 to ANI14		0		Vdd	V
		ANI16 to ANI20		0		EV _{DD0}	V
		Internal reference voltage (2.4 V \leq Vpd \leq 5.5 V, HS (high-speed main) mode)			VBGR Note 4		
		Temperature sensor output voltage (2.4 V \leq Vpp \leq 5.5 V, HS (high-speed main) mode)			V _{TMPS25} Note 4		

Note 1. Excludes quantization error (±1/2 LSB).

Note 2. This value is indicated as a ratio (% FSR) to the full-scale value.

Note 3. When the conversion time is set to 57 μ s (min.) and 95 μ s (max.).

Note 4. Refer to 2.6.2 Temperature sensor characteristics/internal reference voltage characteristic.



3.3.2 Supply current characteristics

(1) Flash ROM: 16 to 64 KB of 30- to 64-pin products

(TA = -40 to +105°C, 2.4 V \leq EVDD0 \leq VDD \leq 5.5 V, Vss = EVsso = 0 V)

Parameter	Symbol			Conditions			MIN.	TYP.	MAX.	Unit
Supply	IDD1	Operat-	HS (high-speed main)	fносо = 64 MHz,	Basic	VDD = 5.0 V		2.4		mA
current		ing mode	mode Note 5	fiH = 32 MHz Note 3	operation	VDD = 3.0 V		2.4		
Note 1				fносо = 32 MHz,	Basic	VDD = 5.0 V		2.1		
				fiH = 32 MHz Note 3	operation	VDD = 3.0 V		2.1		
			HS (high-speed main)	fносо = 64 MHz,	Normal	VDD = 5.0 V		5.1	9.3	mA
			mode Note 5	fiH = 32 MHz Note 3	operation	VDD = 3.0 V		5.1	9.3	
				fносо = 32 MHz,	Normal	VDD = 5.0 V		4.8	8.7	
				fiH = 32 MHz Note 3	operation	VDD = 3.0 V		4.8	8.7	
				fносо = 48 MHz,	Normal	VDD = 5.0 V		4.0	7.3	
				fiH = 24 MHz Note 3	operation	VDD = 3.0 V		4.0	7.3	
				fносо = 24 MHz,	Normal	VDD = 5.0 V		3.8	6.7	
				fiH = 24 MHz Note 3	operation	VDD = 3.0 V		3.8	6.7	
				fносо = 16 MHz,	Normal	VDD = 5.0 V		2.8	4.9	
				fiH = 16 MHz Note 3	operation	VDD = 3.0 V		2.8	4.9	
			HS (high-speed main)	f _{MX} = 20 MHz ^{Note 2} ,	Normal	Square wave input		3.3	5.7	m/
		mode Note 5	VDD = 5.0 V	operation	Resonator connection		3.4	5.8		
			f _{MX} = 20 MHz ^{Note 2} , N	Normal	Square wave input		3.3	5.7		
				V _{DD} = 3.0 V	operation	Resonator connection		3.4	5.8	1
				f _{MX} = 10 MHz ^{Note 2} ,	Normal	Square wave input		2.0	3.4	
			VDD = 5.0 V	operation	Resonator connection		2.1	3.5		
				f _{MX} = 10 MHz Note 2,	Normal	Square wave input		2.0	3.4	1
				VDD = 3.0 V	operation	Resonator connection		2.1	3.5	1
			Subsystem clock	fsue = 32.768 kHz Note 4	Normal	Square wave input		4.7	6.1	μA
			operation	Ta = -40°C	operation	Resonator connection		4.7	6.1	
				fsue = 32.768 kHz Note 4	Normal	Square wave input		4.7	6.1	
				TA = +25°C	operation	Resonator connection		4.7	6.1	
				fsue = 32.768 kHz Note 4	Normal	Square wave input		4.8	6.7	
				TA = +50°C	operation	Resonator connection		4.8	6.7	
			fsub = 32.768 kHz Note 4	Normal	Square wave input		4.8	7.5		
			TA = +70°C	operation	Resonator connection		4.8	7.5	1	
				fsue = 32.768 kHz Note 4	Normal	Square wave input		5.4	8.9	1
				TA = +85°C	operation	Resonator connection		5.4	8.9	1
				fs	fsue = 32.768 kHz Note 4	Normal	Square wave input		7.2	21.0
				TA = +105°C	operation	Resonator connection		7.3	21.1	1

(Notes and Remarks are listed on the next page.)



- Note 1. Total current flowing into VDD, EVDD0, and EVDD1, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD0, and EVDD1, or Vss, EVss0, and EVss1. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, D/A converter, comparator, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
 Note 2. During HALT instruction execution by flash memory.
- Note 3. When high-speed on-chip oscillator and subsystem clock are stopped.
- **Note 4.** When high-speed system clock and subsystem clock are stopped.
- **Note 5.** When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1). The current flowing into the RTC is included. However, not including the current flowing into the 12-bit interval timer and watchdog timer.
- Note 6. Not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer.
- Note 7.Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.
HS (high-speed main) mode: $2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}$ @1 MHz to 32 MHz
 - 2.4 V \leq VDD \leq 5.5 V@1 MHz to 16 MHz
- Note 8. Regarding the value for current to operate the subsystem clock in STOP mode, refer to that in HALT mode.
- Remark 1. fMX: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
- Remark 2. fHOCO: High-speed on-chip oscillator clock frequency (64 MHz max.)
- Remark 3. fin: High-speed on-chip oscillator clock frequency (32 MHz max.)
- Remark 4. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
- Remark 5. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is TA = 25°C



(4) During communication at same potential (simplified I²C mode)

(TA = -40 to +105°C, 2.4 V \leq EV	$IDD0 = EVDD1 \le VD$	$D \leq 5.5 V$, VSS = EVSS0 = E	EVss1 = 0 V)

Parameter	Symbol	Conditions	HS (high-speed	main) mode	Unit
			MIN.	MAX.	
SCLr clock frequency	fsc∟	$\begin{array}{l} 2.7 \ \text{V} \leq E V_{\text{DD0}} \leq 5.5 \ \text{V}, \\ \text{C}_{\text{b}} = 50 \ \text{pF}, \ \text{R}_{\text{b}} = 2.7 \ \text{k}\Omega \end{array}$		400 Note 1	kHz
		$\begin{array}{l} 2.4 \ V \leq EV_{DD0} \leq 5.5 \ V, \\ C_{b} \texttt{=} 100 \ pF, \ R_{b} \texttt{=} 3 \ k\Omega \end{array}$		100 Note 1	kHz
Hold time when SCLr = "L"	tLOW	$\begin{array}{l} 2.7 \ \text{V} \leq E V_{\text{DD0}} \leq 5.5 \ \text{V}, \\ \text{C}_{\text{b}} = 50 \ \text{pF}, \ \text{R}_{\text{b}} = 2.7 \ \text{k}\Omega \end{array}$	1200		ns
		$\begin{array}{l} 2.4V \leq EV_{DD0} \leq 5.5 \; V, \\ C_{b} = 100 \; pF, \; R_{b} = 3 \; k\Omega \end{array}$	4600		ns
Hold time when SCLr = "H"	tніgн	$\begin{array}{l} 2.7 \ \text{V} \leq E V_{\text{DD0}} \leq 5.5 \ \text{V}, \\ \text{C}_{\text{b}} = 50 \ \text{pF}, \ \text{R}_{\text{b}} = 2.7 \ \text{k}\Omega \end{array}$	1200		ns
		$2.4 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V},$ Cb = 100 pF, Rb = 3 k Ω	4600		ns
Data setup time (reception)	tsu: dat	$\begin{array}{l} 2.7 \ \text{V} \leq E V_{\text{DD0}} \leq 5.5 \ \text{V}, \\ \text{C}_{\text{b}} = 50 \ \text{pF}, \ \text{R}_{\text{b}} = 2.7 \ \text{k}\Omega \end{array}$	1/fMCK + 220 Note 2		ns
		$\begin{array}{l} 2.4V \leq EV_{DD0} \leq 5.5 \; V, \\ C_{b} = 100 \; pF, \; R_{b} = 3 \; k\Omega \end{array}$	1/fMCK + 580 Note 2		ns
Data hold time (transmission)	thd: dat	$\begin{array}{l} 2.7 \ \text{V} \leq E V_{\text{DD0}} \leq 5.5 \ \text{V}, \\ \text{C}_{\text{b}} = 50 \ \text{pF}, \ \text{R}_{\text{b}} = 2.7 \ \text{k}\Omega \end{array}$	0	770	ns
		$\begin{array}{l} 2.4 \ V \leq EV_{DD0} \leq 5.5 \ V, \\ C_{b} \texttt{=} 100 \ pF, \ R_{b} \texttt{=} 3 \ k\Omega \end{array}$	0	1420	ns

Note 1. The value must also be equal to or less than fMCK/4.

Note 2. Set the fMCK value to keep the hold time of SCLr = "L" and SCLr = "H".

Caution Select the normal input buffer and the N-ch open drain output (VDD tolerance (for the 30- to 52-pin products)/EVDD tolerance (for the 64- to 100-pin products)) mode for the SDAr pin and the normal output mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register h (POMh).

(**Remarks** are listed on the next page.)



(3) When reference voltage (+) = VDD (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = Vss (ADREFM = 0), target pin: ANI0 to ANI14, ANI16 to ANI20, internal reference voltage, and temperature sensor output voltage

(TA = -40 to +105°C, 2.4 V \leq EVDD0 = EVDD1 \leq VDD \leq 5.5 V, Vss = EVss0 = EVss1 = 0 V, Reference voltage (+) = VDD, Reference voltage (-) = Vss)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error Note 1	AINL	10-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$		1.2	±7.0	LSB
Conversion time	tconv	10-bit resolution	$3.6~V \leq V_{DD} \leq 5.5~V$	2.125		39	μs
		Target pin: ANI0 to ANI14, ANI16 to ANI20	$2.7~V \leq V_{DD} \leq 5.5~V$	3.1875		39	μs
			$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μs
		10-bit resolution	$3.6~V \leq V_{DD} \leq 5.5~V$	2.375		39	μs
		Target pin: internal reference voltage, and temperature sensor output voltage	$2.7~V \leq V_{DD} \leq 5.5~V$	3.5625		39	μs
		(HS (high-speed main) mode)	$2.4~\text{V} \leq \text{V}_\text{DD} \leq 5.5~\text{V}$	17		39	μs
Zero-scale error Notes 1, 2	Ezs	10-bit resolution	$2.4~\text{V} \leq \text{V}_\text{DD} \leq 5.5~\text{V}$			±0.60	%FSR
Full-scale error Notes 1, 2	Efs	10-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±0.60	%FSR
Integral linearity error Note 1	ILE	10-bit resolution	$2.4~\text{V} \leq \text{V}_\text{DD} \leq 5.5~\text{V}$			±4.0	LSB
Differential linearity error Note 1	DLE	10-bit resolution	$2.4~\text{V} \leq \text{V}_{\text{DD}} \leq 5.5~\text{V}$			±2.0	LSB
Analog input voltage	VAIN	ANI0 to ANI14	1	0		Vdd	V
		ANI16 to ANI20		0		EV _{DD0}	V
		Internal reference voltage (2.4 V \leq VDD \leq 5.5 V, HS (high-speed main) mode)			V _{BGR} Note 3		
		Temperature sensor output voltage (2.4 V \leq V _{DD} \leq 5.5 V, HS (high-speed main) mode)			VTMPS25 Note 3		

Note 1. Excludes quantization error (±1/2 LSB).

Note 2. This value is indicated as a ratio (% FSR) to the full-scale value.

Note 3. Refer to 3.6.2 Temperature sensor characteristics/internal reference voltage characteristic.



3.6.2 Temperature sensor characteristics/internal reference voltage characteristic

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	VTMPS25	Setting ADS register = 80H, T _A = +25°C		1.05		V
Internal reference voltage	Vbgr	Setting ADS register = 81H	1.38	1.45	1.5	V
Temperature coefficient	FVTMPS	Temperature sensor that depends on the temperature		-3.6		mV/°C
Operation stabilization wait time	tamp		5			μs

(TA = -40 to +105°C, 2.4 V \leq VDD \leq 5.5 V, Vss = EVsso = EVss1 = 0 V, HS (high-speed main) mode)

3.6.3 D/A converter characteristics

(TA = -40 to +105°C, 2.4 V \leq EVsso = EVss1 \leq VDD \leq 5.5 V, Vss = EVsso = EVss1 = 0 V)

Parameter	Symbol	Cor	nditions	MIN.	TYP.	MAX.	Unit
Resolution	RES					8	bit
Overall error	AINL	Rload = 4 M Ω	$2.4~V \leq V_{DD} \leq 5.5~V$			±2.5	LSB
		Rload = 8 MΩ	$2.4~V \leq V \text{DD} \leq 5.5~V$			±2.5	LSB
Settling time	tset	Cload = 20 pF	$2.7~V \leq V\text{DD} \leq 5.5~V$			3	μs
			$2.4~V \leq V_{DD} < 2.7~V$			6	μs

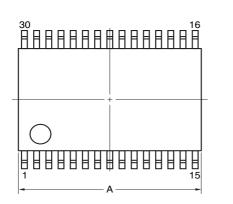


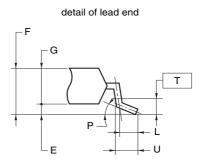
4. PACKAGE DRAWINGS

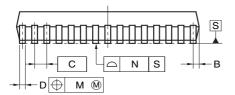
4.1 30-pin products

R5F104AAASP, R5F104ACASP, R5F104ADASP, R5F104AEASP, R5F104AFASP, R5F104AGASP R5F104AADSP, R5F104ACDSP, R5F104ADDSP, R5F104AEDSP, R5F104AFDSP, R5F104AGDSP R5F104AAGSP, R5F104ACGSP, R5F104ADGSP, R5F104AEGSP, R5F104AFGSP, R5F104AGGSP

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LSSOP30-0300-0.65	PLSP0030JB-B	S30MC-65-5A4-3	0.18

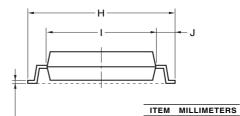






NOTE

Each lead centerline is located within 0.13 mm of its true position (T.P.) at maximum material condition.



·κ

Α 9.85±0.15 в 0.45 MAX С 0.65 (T.P.) $0.24_{-0.07}^{+0.08}$ D F 0.1±0.05 F 1.3±0.1 G 1.2 8.1±0.2 Н 6.1±0.2 I 1.0±0.2 J 0.17±0.03 κ L 0.5 0.13 Μ Ν 0.10 Р 3°+5° 0.25 т 0.6±0.15 U

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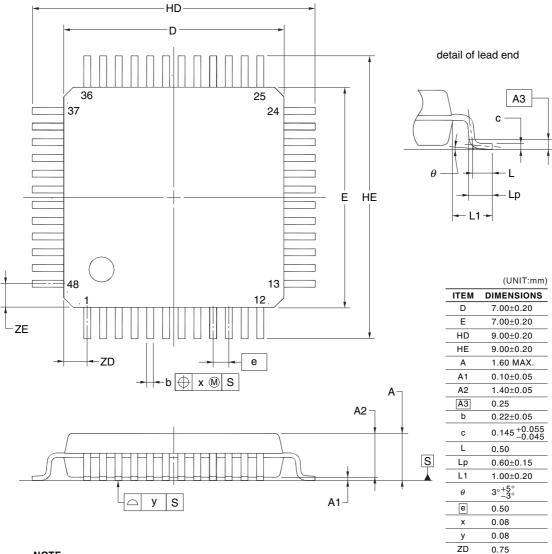
4.6 48-pin products

R5F104GAAFB, R5F104GCAFB, R5F104GDAFB, R5F104GEAFB, R5F104GFAFB, R5F104GGAFB, R5F104GHAFB, R5F104GJAFB

R5F104GADFB, R5F104GCDFB, R5F104GDDFB, R5F104GEDFB, R5F104GFDFB, R5F104GGDFB, R5F104GHDFB, R5F104GJDFB

R5F104GAGFB, R5F104GCGFB, R5F104GDGFB, R5F104GEGFB, R5F104GFGFB, R5F104GGGFB, R5F104GHGFB, R5F104GJGFB

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LFQFP48-7x7-0.50	PLQP0048KF-A	P48GA-50-8EU-1	0.16



NOTE

Each lead centerline is located within 0.08 mm of its true position at maximum material condition.



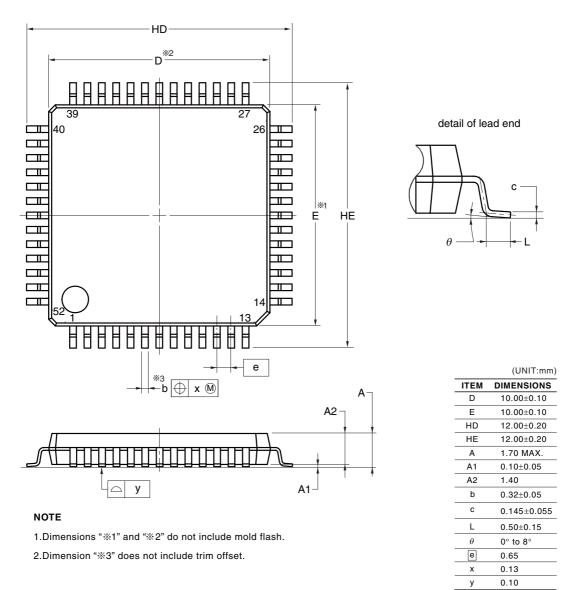
ZE

0.75

4.7 52-pin products

R5F104JCAFA, R5F104JDAFA, R5F104JEAFA, R5F104JFAFA, R5F104JGAFA, R5F104JHAFA, R5F104JJAFA R5F104JCDFA, R5F104JDDFA, R5F104JEDFA, R5F104JFDFA, R5F104JGDFA, R5F104JHDFA, R5F104JJDFA R5F104JCGFA, R5F104JDGFA, R5F104JEGFA, R5F104JFGFA, R5F104JGGFA, R5F104JHGFA, R5F104JJGFA

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LQFP52-10x10-0.65	PLQP0052JA-A	P52GB-65-GBS-1	0.3

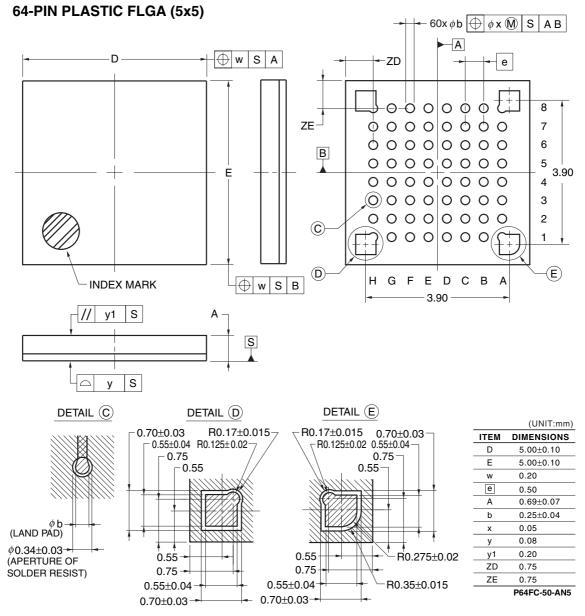


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R5F104LCALA, R5F104LDALA, R5F104LEALA, R5F104LFALA, R5F104LGALA, R5F104LHALA, R5F104LJALA R5F104LKALA, R5F104LLALA

R5F104LCGLA,R5F104LDGLA, R5F104LEGLA, R5F104LFGLA, R5F104LGGLA, R5F104LHGLA, R5F104LJGLA R5F104LKGLA, R5F104LLGLA



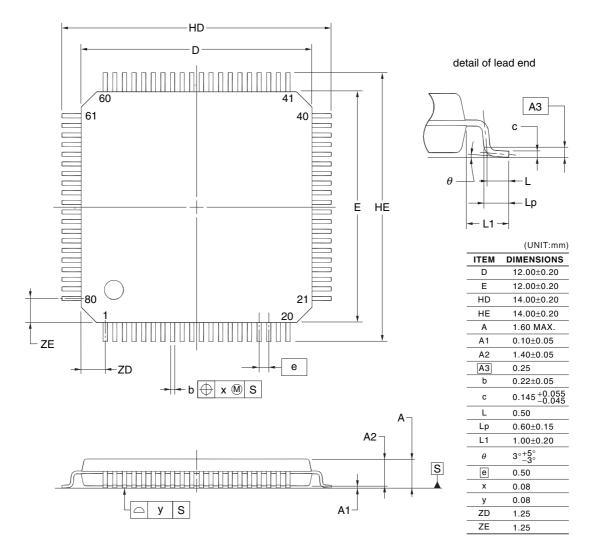
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RENESAS

4.9 80-pin products

R5F104MFAFB, R5F104MGAFB, R5F104MHAFB, R5F104MJAFB R5F104MFDFB, R5F104MGDFB, R5F104MHDFB, R5F104MJDFB R5F104MFGFB, R5F104MGGFB, R5F104MHGFB, R5F104MJGFB

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LFQFP80-12x12-0.50	PLQP0080KE-A	P80GK-50-8EU-2	0.53



NOTE

Each lead centerline is located within 0.08 mm of its true position at maximum material condition.

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